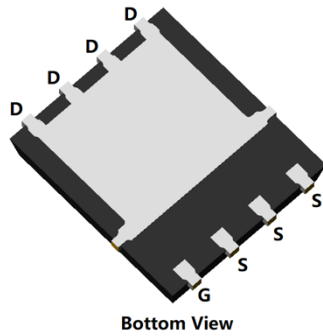
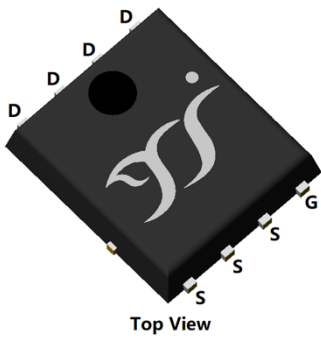
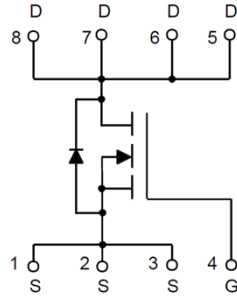


## N-Channel Enhancement Mode Field Effect Transistor



PDFN5060-8L



### Product Summary

- $V_{DS}$  30V
- $I_D$  50A
- $R_{DS(ON)}$  (at  $V_{GS}=10V$ ) <4.7mohm
- $R_{DS(ON)}$  (at  $V_{GS}=4.5V$ ) <6.0mohm
- 100% UIS Tested
- 100%  $\nabla V_{DS}$  Tested

### General Description

- Trench Power LV MOSFET technology
- Excellent package for heat dissipation
- High density cell design for low  $R_{DS(ON)}$

### Applications

- High current load applications
- Load switching
- Hard switched and high frequency circuits
- Uninterruptible power supply

### ■ Absolute Maximum Ratings ( $T_A=25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-source Voltage	$V_{DS}$	30	V
Gate-source Voltage	$V_{GS}$	$\pm 20$	V
Drain Current	$I_D$	$T_C=25^\circ\text{C}$	50
		$T_C=100^\circ\text{C}$	31.6
Pulsed Drain Current <sup>A</sup>	$I_{DM}$	190	A
Total Power Dissipation	$P_D$	$T_C=25^\circ\text{C}$	45
		$T_C=100^\circ\text{C}$	17.8
Single Pulse Avalanche Energy <sup>B</sup>	$E_{AS}$	196	mJ
Thermal Resistance Junction-to-Case <sup>C</sup>	$R_{\theta JC}$	2.8	$^\circ\text{C}/\text{W}$
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55~+150	$^\circ\text{C}$

### ■ Ordering Information (Example)

PREFERRED P/N	PACKING CODE	Marking	MINIMUM PACKAGE(pcs)	INNER BOX QUANTITY(pcs)	OUTER CARTON QUANTITY(pcs)	DELIVERY MODE
YJG50N03A	F1	YJG50N03A	5000	10000	100000	13" reel



# YJG50N03A

## ■ Electrical Characteristics ( $T_J=25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Conditions	Min	Typ	Max	Units
<b>Static Parameter</b>						
Drain-Source Breakdown Voltage	$BV_{DSS}$	$V_{GS}=0V, I_D=250\mu A$	30			V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS}=30V, V_{GS}=0V$			1	$\mu A$
Gate-Body Leakage Current	$I_{GSS}$	$V_{GS}=\pm 20V, V_{DS}=0V$			$\pm 100$	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=250\mu A$	1.0	1.5	2.5	V
Static Drain-Source On-Resistance	$R_{DS(on)}$	$V_{GS}=10V, I_D=15A$		3.9	4.7	m $\Omega$
		$V_{GS}=4.5V, I_D=15A$		5.0	6.0	
Diode Forward Voltage	$V_{SD}$	$I_S=15A, V_{GS}=0V$		0.85	1.2	V
Maximum Body-Diode Continuous Current	$I_S$				50	A
<b>Dynamic Parameters</b>						
Input Capacitance	$C_{iss}$	$V_{DS}=15V, V_{GS}=0V, f=1\text{MHz}$		2504		pF
Output Capacitance	$C_{oss}$			323		
Reverse Transfer Capacitance	$C_{rss}$			283		
<b>Switching Parameters</b>						
Total Gate Charge	$Q_g$	$V_{GS}=10V, V_{DS}=15V, I_D=20A$		54		nC
Gate-Source Charge	$Q_{gs}$			8.5		
Gate-Drain Charge	$Q_{gd}$			10.2		
Reverse Recovery Charge	$Q_{rr}$	$I_F=15A, di/dt=100A/\mu s$		6.5		ns
Reverse Recovery Time	$t_{rr}$			15		
Turn-on Delay Time	$t_{D(on)}$	$V_{GS}=10V, V_{DD}=20V, I_D=2A, R_{GEN}=3\Omega$		11		ns
Turn-on Rise Time	$t_r$			20		
Turn-off Delay Time	$t_{D(off)}$			41		
Turn-off fall Time	$t_f$			25		

A. Pulse Test: Pulse Width  $\leq 300\mu s$ , Duty cycle  $\leq 2\%$ .

B.  $T_J=25^\circ\text{C}$ ,  $V_{DD}=25V$ ,  $V_{GS}=10V$ ,  $L=2\text{mH}$ ,  $I_{AS}=14A$ .

C.  $R_{\theta JA}$  is the sum of the junction-to-case and case-to-ambient thermal resistance, where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{\theta JC}$  is guaranteed by design, while  $R_{\theta JA}$  is determined by the board design. The maximum rating presented here is based on mounting on a 1 in 2 pad of 2oz copper.



■ Typical Performance Characteristics

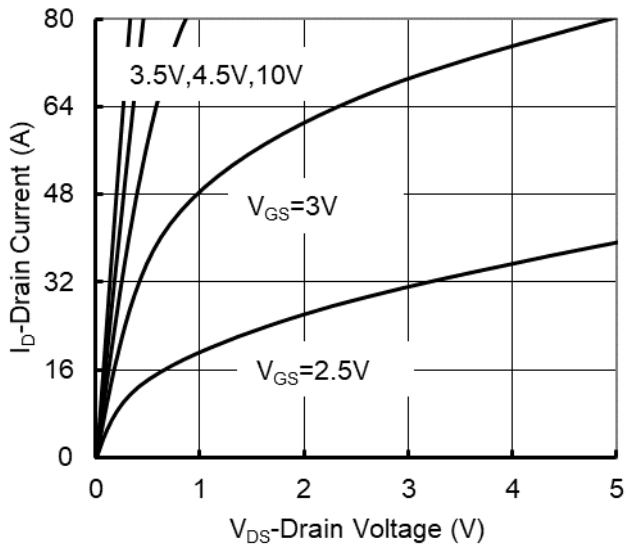


Figure 1. Output Characteristics

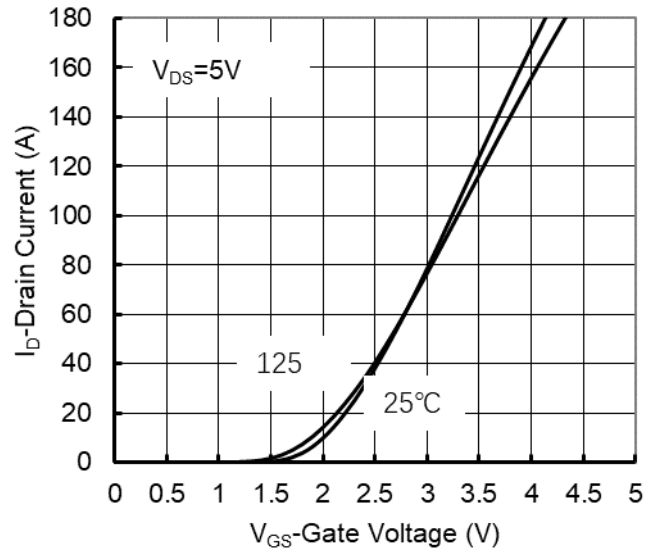


Figure 2. Transfer Characteristics

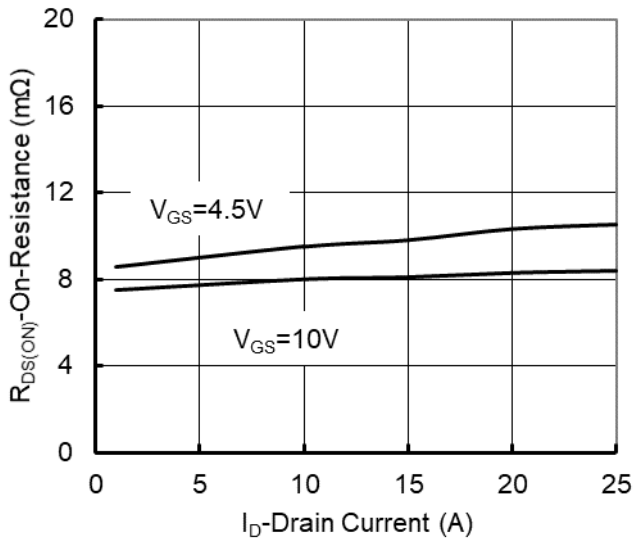


Figure 3. On-Resistance vs. Drain Current and Gate Voltage

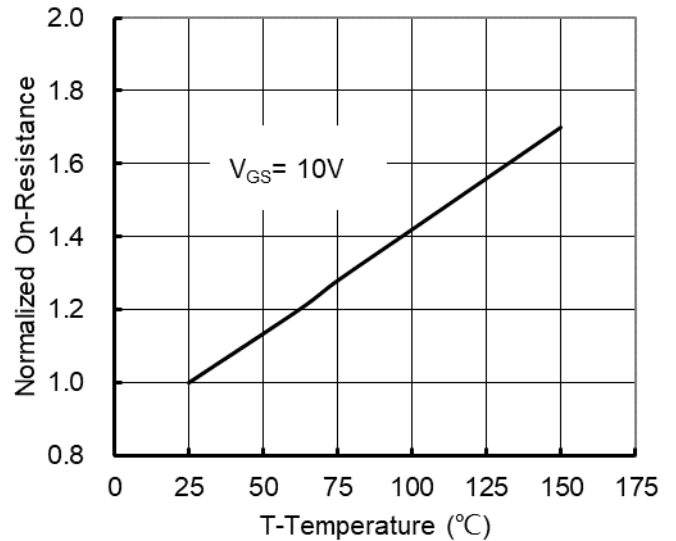


Figure 4. On-Resistance vs. Junction Temperature

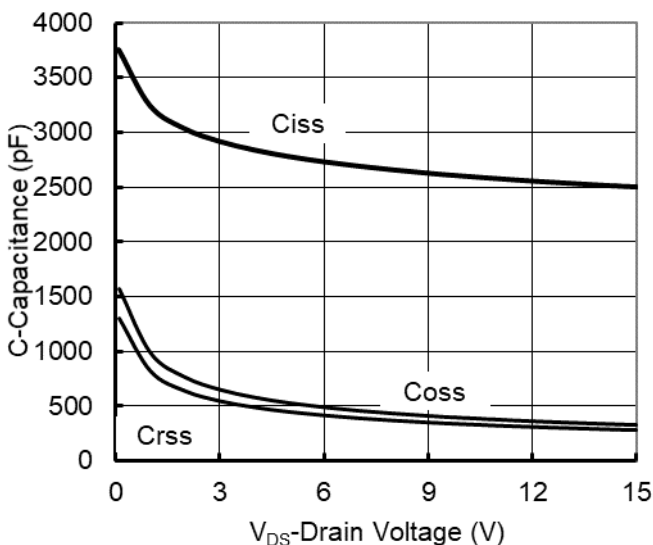


Figure 5. Capacitance Characteristics

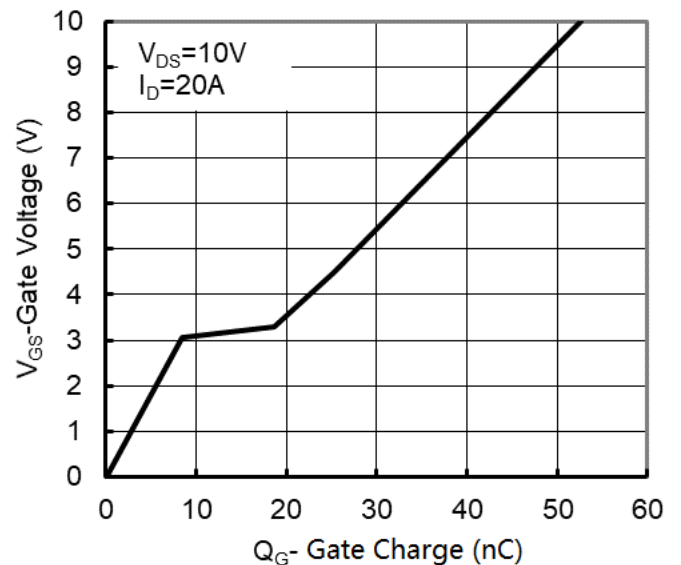


Figure 6. Gate Charge



# YJG50N03A

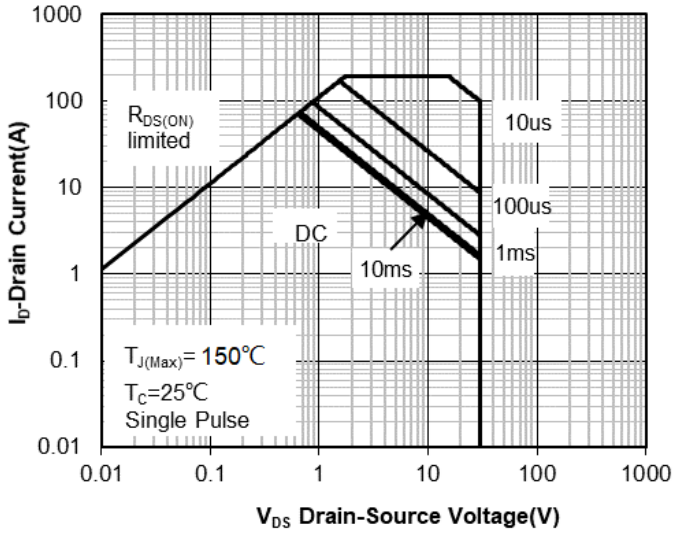


Figure 7. Safe Operation Area

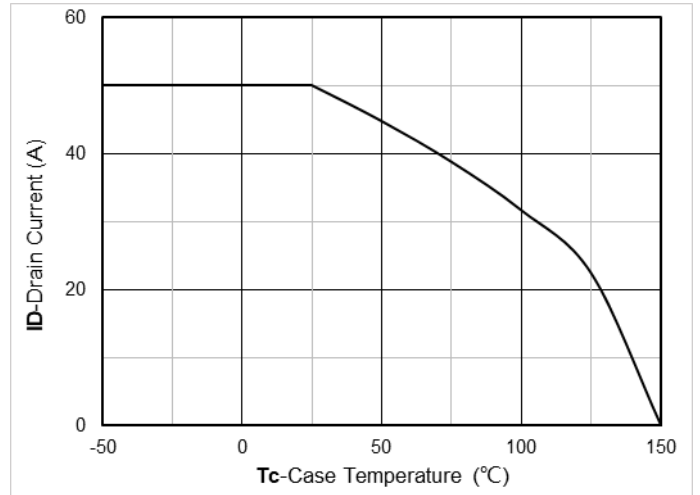


Figure 8. Maximum Continuous Drain Current vs Case Temperature

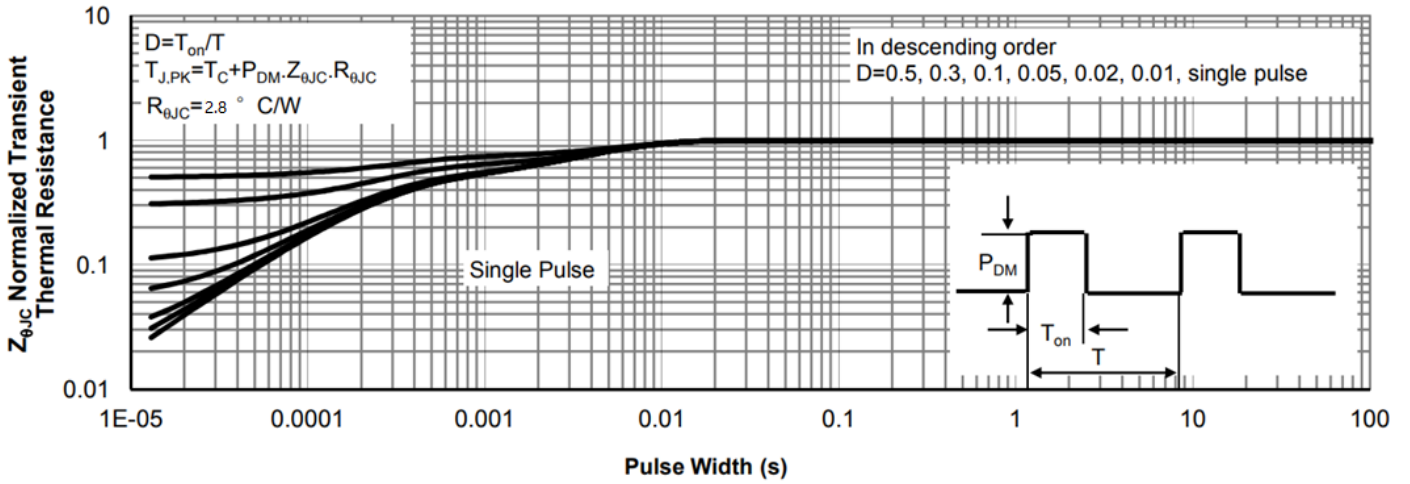
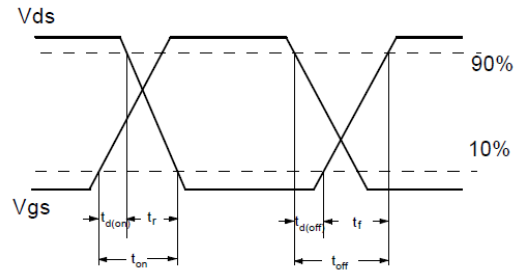
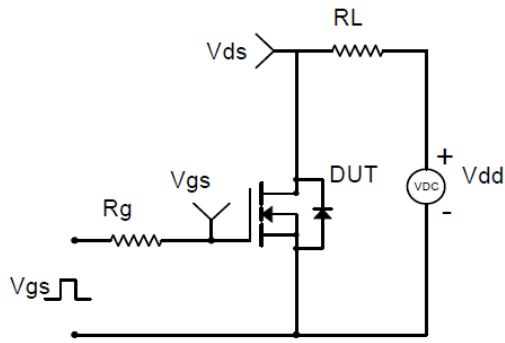
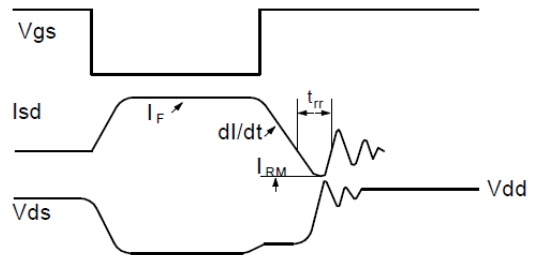
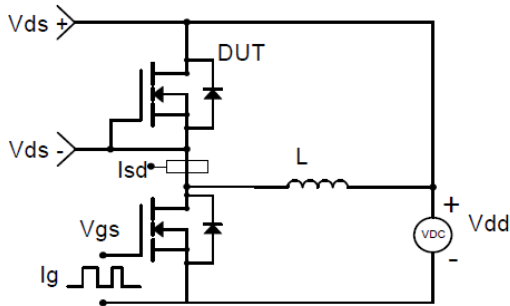


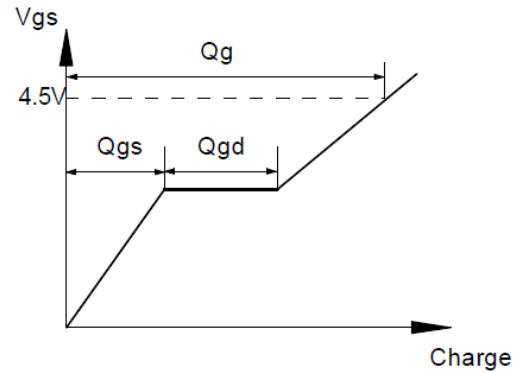
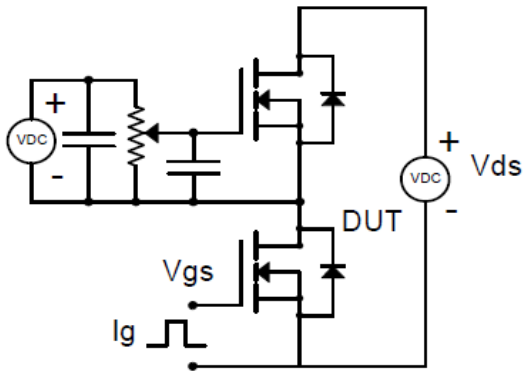
Figure 9. Normalized Maximum Transient Thermal Impedance



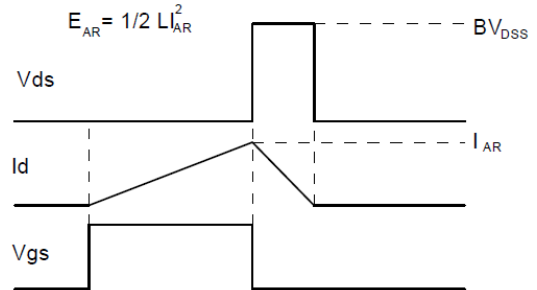
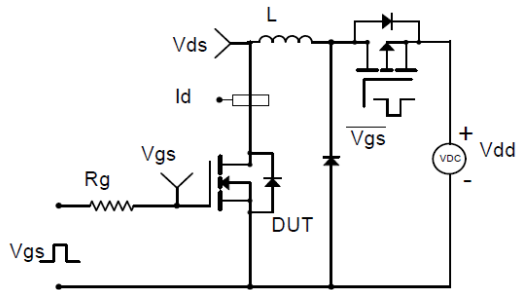
**Resistive Switching Test Circuit & Waveforms**



**Diode Recovery Test Circuit & Waveforms**



**Gate Charge Test Circuit & Waveform**

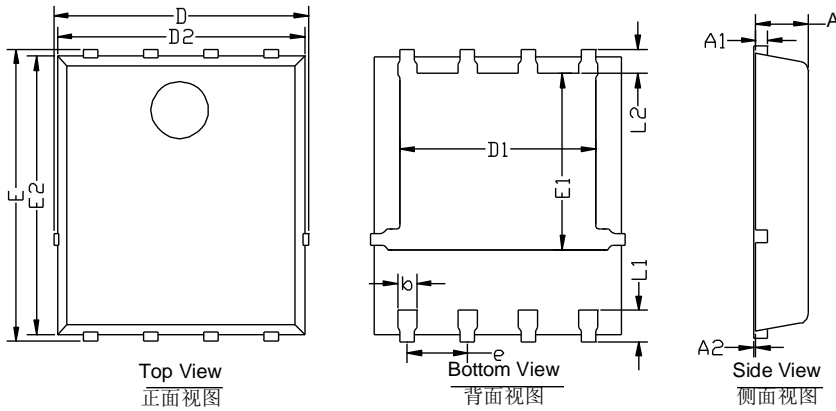


**Unclamped Inductive Switching (UIS) Test Circuit & Waveforms**

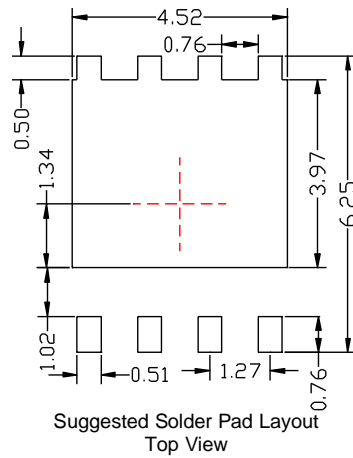


# YJG50N03A

## ■ PDFN5060-8L Package Information



SYMBOL	MILLIMETER		
	MIN	NOM	MAX
D	5.15	5.35	5.55
E	5.95	6.15	6.35
A	1.00	1.10	1.20
A1	0.254 BSC		
A2			0.10
D1	3.92	4.12	4.32
E1	3.52	3.72	3.92
D2	5.00	5.20	5.40
E2	5.66	5.86	6.06
L1	0.56	0.66	0.76
L2	0.50 BSC		
b	0.31	0.41	0.51
e	1.27 BSC		



- Note:
1. Controlling dimension: in millimeters.
  2. General tolerance:  $\pm 0.10$ mm.
  3. The pad layout is for reference purposes only.



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